Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	291
Number of Logic Elements/Cells	2910
Total RAM Bits	59904
Number of I/O	104
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1c3t144c6

functions. Another special packing mode allows the register output to feed back into the LUT of the same LE so that the register is packed with its own fan-out LUT. This provides another mechanism for improved fitting. The LE can also drive out registered and unregistered versions of the LUT output.

LUT Chain and Register Chain

In addition to the three general routing outputs, the LEs within a LAB have LUT chain and register chain outputs. LUT chain connections allow LUTs within the same LAB to cascade together for wide input functions. Register chain outputs allow registers within the same LAB to cascade together. The register chain output allows a LAB to use LUTs for a single combinatorial function and the registers to be used for an unrelated shift register implementation. These resources speed up connections between LABs while saving local interconnect resources. "MultiTrack Interconnect" on page 2–12 for more information on LUT chain and register chain connections.

addnsub Signal

The LE's dynamic adder/subtractor feature saves logic resources by using one set of LEs to implement both an adder and a subtractor. This feature is controlled by the LAB-wide control signal `addnsub`. The `addnsub` signal sets the LAB to perform either A + B or A –B. The LUT computes addition; subtraction is computed by adding the two's complement of the intended subtractor. The LAB-wide signal converts to two's complement by inverting the B bits within the LAB and setting carry-in = 1 to add one to the least significant bit (LSB). The LSB of an adder/subtractor must be placed in the first LE of the LAB, where the LAB-wide `addnsub` signal automatically sets the carry-in to 1. The Quartus II Compiler automatically places and uses the adder/subtractor feature when using adder/subtractor parameterized functions.

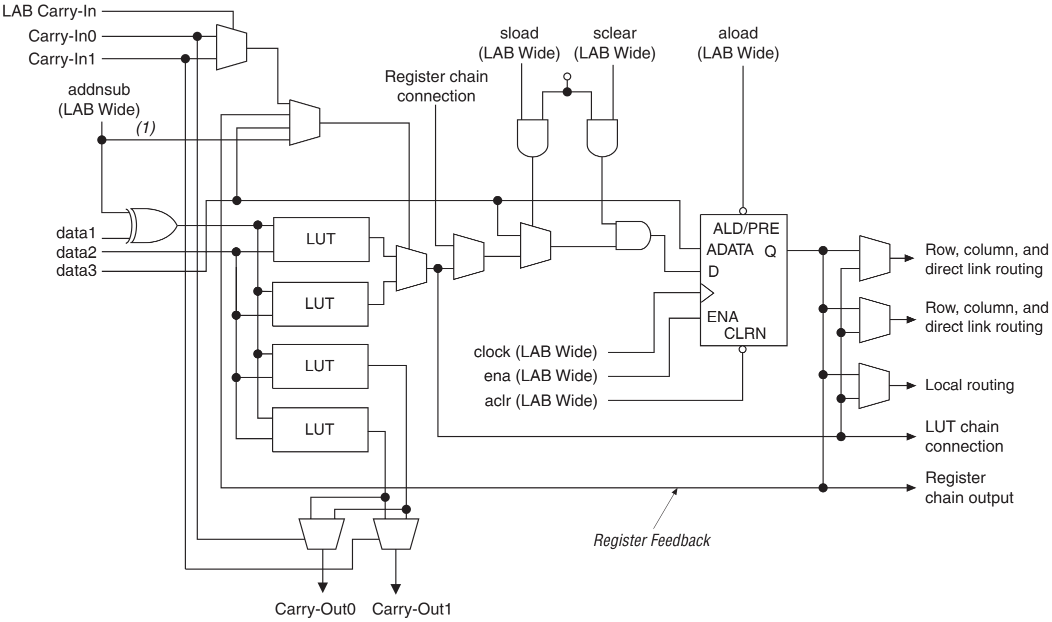
LE Operating Modes

The Cyclone LE can operate in one of the following modes:

- Normal mode
- Dynamic arithmetic mode

Each mode uses LE resources differently. In each mode, eight available inputs to the LE—the four data inputs from the LAB local interconnect, `carry-in0` and `carry-in1` from the previous LE, the LAB carry-in from the previous carry-chain LAB, and the register chain connection—are directed to different destinations to implement the desired logic function. LAB-wide signals provide clock, asynchronous clear, asynchronous

Figure 2–7. LE in Dynamic Arithmetic Mode



Note to Figure 2–7:

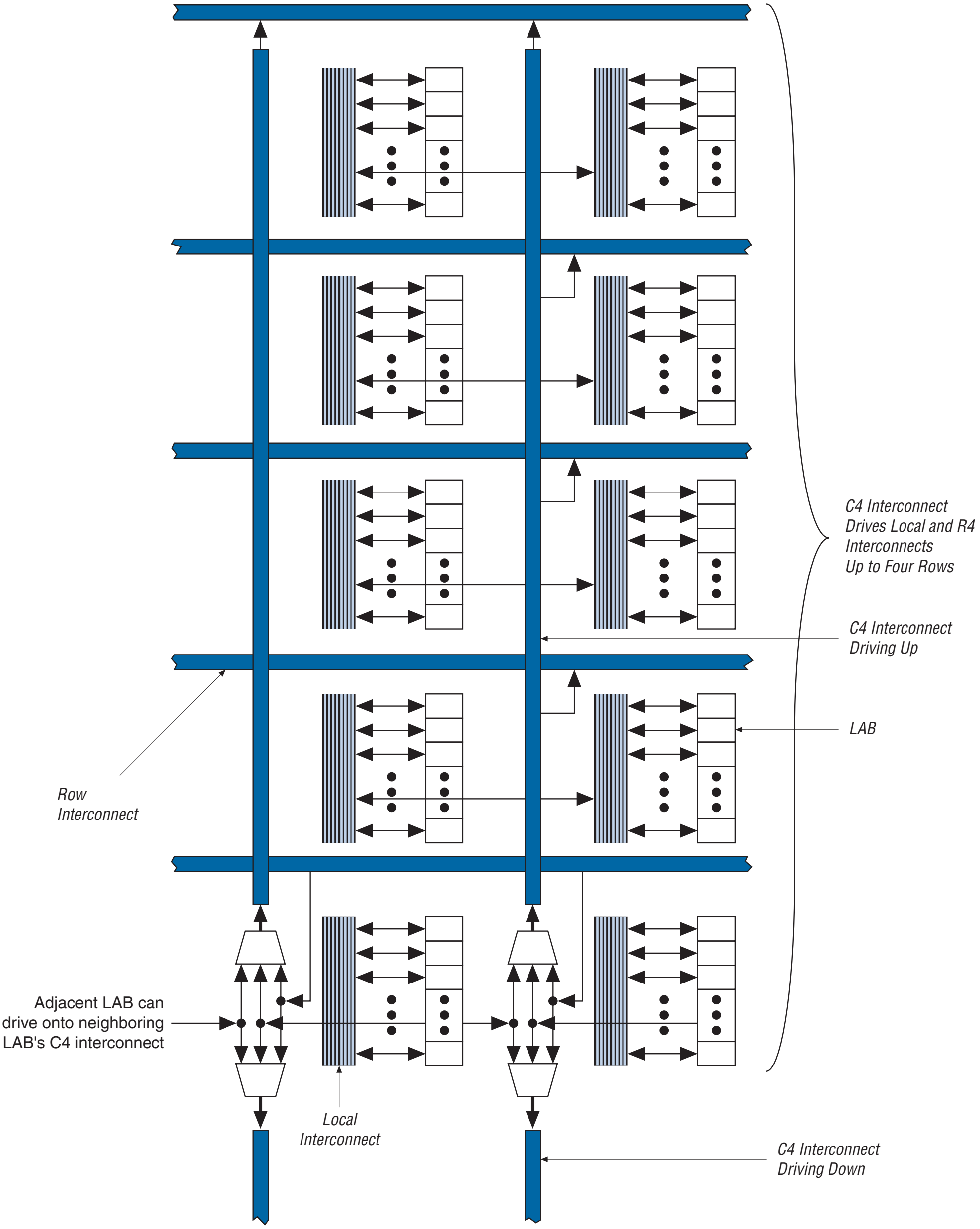
(1) The `addnsub` signal is tied to the carry input for the first LE of a carry chain only.

Carry-Select Chain

The carry-select chain provides a very fast carry-select function between LEs in dynamic arithmetic mode. The carry-select chain uses the redundant carry calculation to increase the speed of carry functions. The LE is configured to calculate outputs for a possible carry-in of 0 and carry-in of 1 in parallel. The `carry-in0` and `carry-in1` signals from a lower-order bit feed forward into the higher-order bit via the parallel carry chain and feed into both the LUT and the next portion of the carry chain. Carry-select chains can begin in any LE within a LAB.

The speed advantage of the carry-select chain is in the parallel pre-computation of carry chains. Since the LAB carry-in selects the precomputed carry chain, not every LE is in the critical path. Only the propagation delays between LAB carry-in generation (LE 5 and LE 10) are now part of the critical path. This feature allows the Cyclone architecture to implement high-speed counters, adders, multipliers, parity functions, and comparators of arbitrary width.

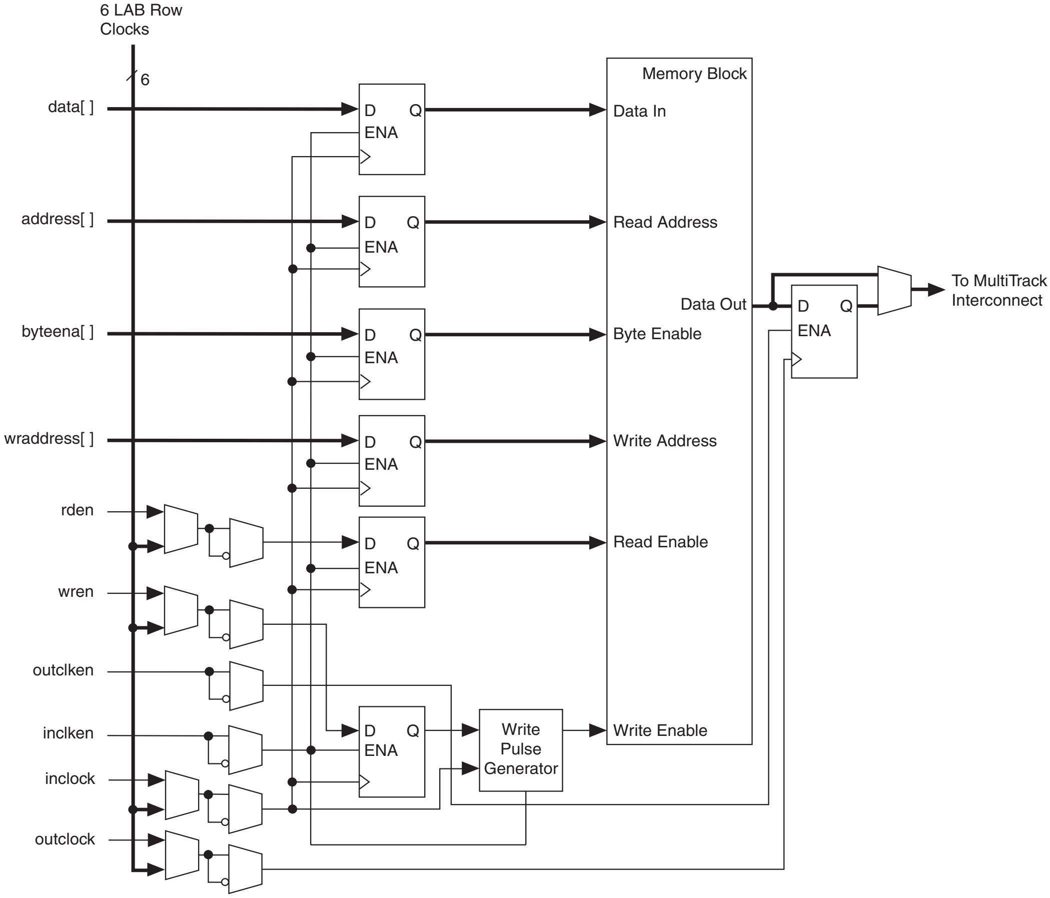
Figure 2–11. C4 Interconnect Connections Note (1)



Note to Figure 2–11:

(1) Each C4 interconnect can drive either up or down four rows.

Figure 2–19. Input/Output Clock Mode in Simple Dual-Port Mode *Notes (1), (2)*



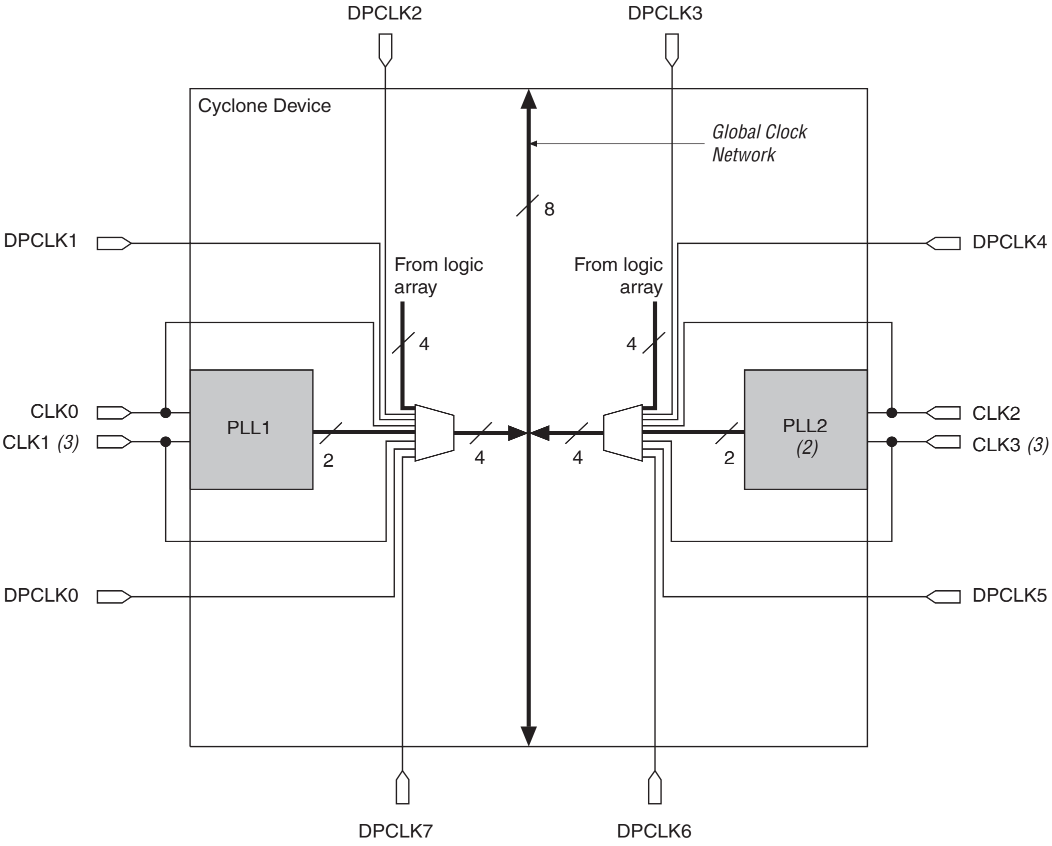
Notes to Figure 2–19:

(1) All registers shown except the rden register have asynchronous clear ports.

(2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

The eight global clock lines in the global clock network drive throughout the entire device. The global clock network can provide clocks for all resources within the device—IOEs, LEs, and memory blocks. The global clock lines can also be used for control signals, such as clock enables and synchronous or asynchronous clears fed from the external pin, or DQS signals for DDR SDRAM or FCRAM interfaces. Internal logic can also drive the global clock network for internally generated global clocks and asynchronous clears, clock enables, or other control signals with large fanout. Figure 2–22 shows the various sources that drive the global clock network.

Figure 2–22. Global Clock Generation *Note (1)*



Notes to Figure 2–22:

(1) The EP1C3 device in the 100-pin TQFP package has five `DPCLK` pins (`DPCLK2`, `DPCLK3`, `DPCLK4`, `DPCLK6`, and `DPCLK7`).
(2) EP1C3 devices only contain one PLL (PLL 1).
(3) The EP1C3 device in the 100-pin TQFP package does not have dedicated clock pins `CLK1` and `CLK3`.

Table 2–6 shows the PLL features in Cyclone devices. Figure 2–25 shows a Cyclone PLL.

Table 2–6. Cyclone PLL Features

Feature	PLL Support
Clock multiplication and division	$m/(n \times$ post-scale counter$)$ *(1)*
Phase shift	Down to 125-ps increments *(2)*, *(3)*
Programmable duty cycle	Yes
Number of internal clock outputs	2
Number of external clock outputs	One differential or one single-ended *(4)*

Notes to Table 2–6:

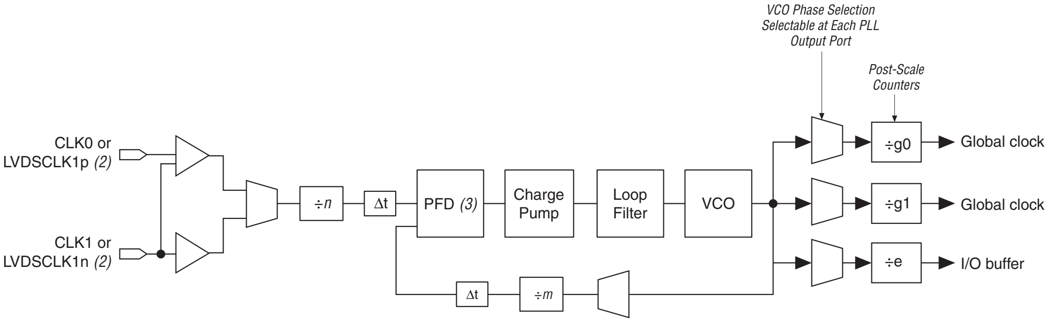
(1) The m counter ranges from 2 to 32. The n counter and the post-scale counters range from 1 to 32.

(2) The smallest phase shift is determined by the voltage-controlled oscillator (VCO) period divided by 8.

(3) For degree increments, Cyclone devices can shift all output frequencies in increments of 45°. Smaller degree increments are possible depending on the frequency and divide parameters.

(4) The EP1C3 device in the 100-pin TQFP package does not support external clock output. The EP1C6 device in the 144-pin TQFP package does not support external clock output from PLL2.

Figure 2–25. Cyclone PLL Note (1)



Notes to Figure 2–25:

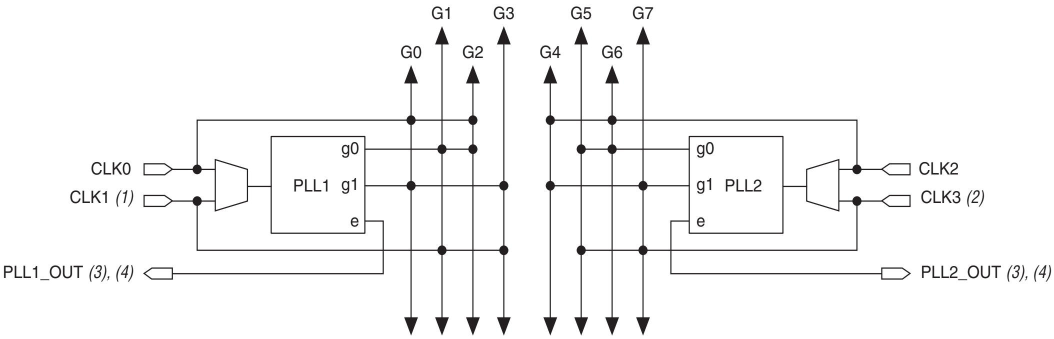
(1) The EP1C3 device in the 100-pin TQFP package does not support external outputs or LVDS inputs. The EP1C6 device in the 144-pin TQFP package does not support external output from PLL2.

(2) LVDS input is supported via the secondary function of the dedicated clock pins. For PLL 1, the `CLK0` pin's secondary function is `LVDSCLK1p` and the `CLK1` pin's secondary function is `LVDSCLK1n`. For PLL 2, the `CLK2` pin's secondary function is `LVDSCLK2p` and the `CLK3` pin's secondary function is `LVDSCLK2n`.

(3) PFD: phase frequency detector.

Figure 2–26 shows the PLL global clock connections.

Figure 2–26. Cyclone PLL Global Clock Connections



Notes to Figure 2–26:

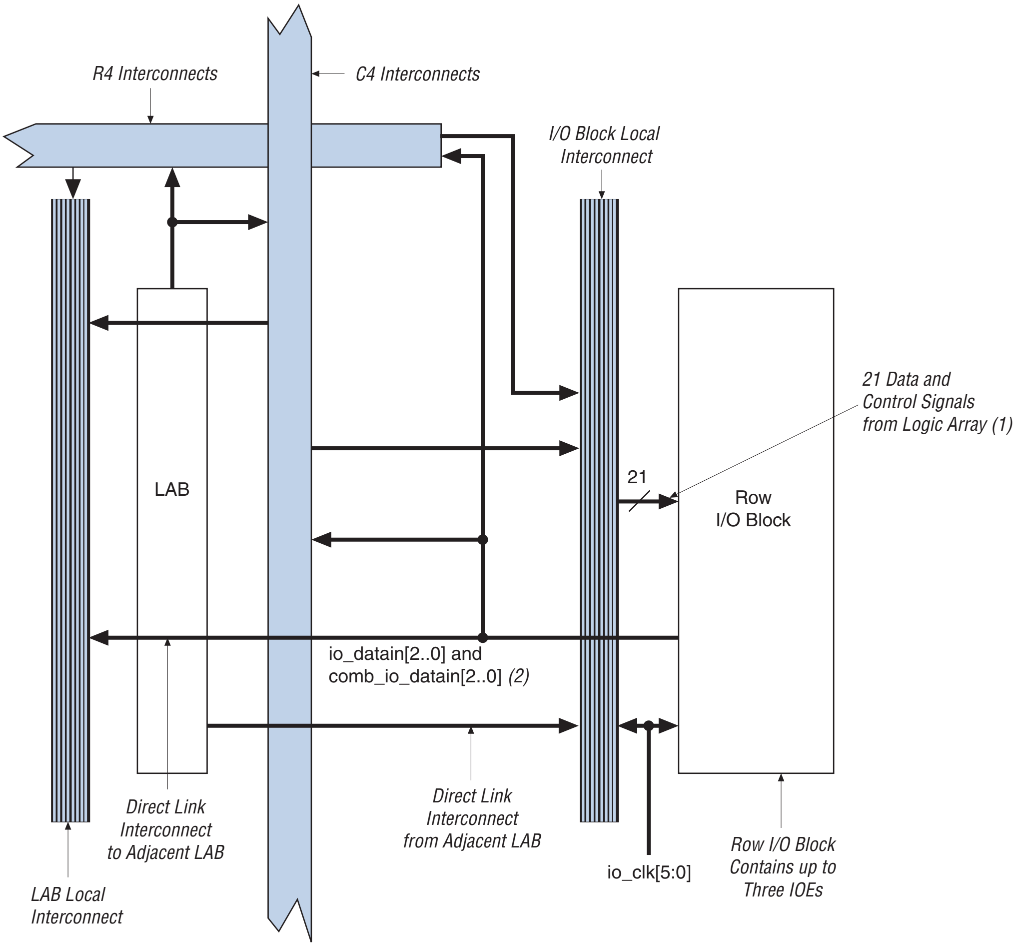
(1) PLL 1 supports one single-ended or LVDS input via pins `CLK0` and `CLK1`.
(2) PLL2 supports one single-ended or LVDS input via pins `CLK2` and `CLK3`.
(3) `PLL1_OUT` and `PLL2_OUT` support single-ended or LVDS output. If external output is not required, these pins are available as regular user I/O pins.
(4) The EP1C3 device in the 100-pin TQFP package does not support external clock output. The EP1C6 device in the 144-pin TQFP package does not support external clock output from PLL2.

Table 2–7 shows the global clock network sources available in Cyclone devices.

Table 2–7. Global Clock Network Sources (Part 1 of 2)

Source		GCLK0	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7
PLL Counter Output	PLL1 G0	—	✓	✓	—	—	—	—	—
	PLL1 G1	✓	—	—	✓	—	—	—	—
	PLL2 G0 *(1)*	—	—	—	—	—	✓	✓	—
	PLL2 G1 *(1)*	—	—	—	—	✓	—	—	✓
Dedicated Clock Input Pins	CLK0	✓	—	✓	—	—	—	—	—
	CLK1 *(2)*	—	✓	—	✓	—	—	—	—
	CLK2	—	—	—	—	✓	—	✓	—
	CLK3 *(2)*	—	—	—	—	—	✓	—	✓

Figure 2–28. Row I/O Block Connection to the Interconnect



Notes to Figure 2–28:

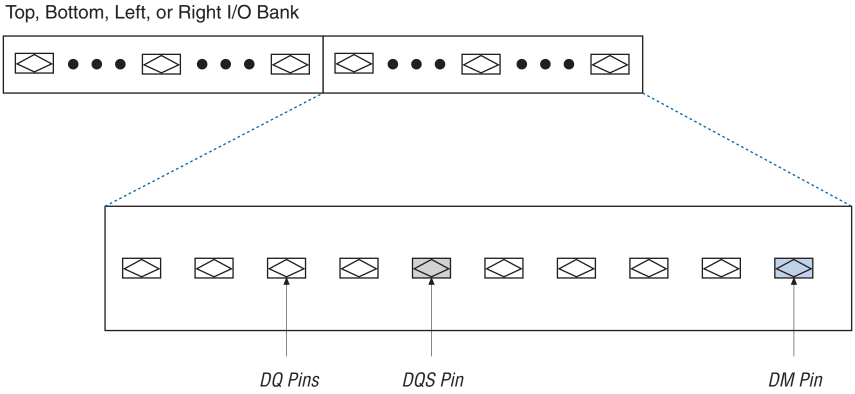
(1) The 21 data and control signals consist of three data out lines, `io_dataout[2..0]`, three output enables, `io_coe[2..0]`, three input clock enables, `io_cce_in[2..0]`, three output clock enables, `io_cce_out[2..0]`, three clocks, `io_cclk[2..0]`, three asynchronous clear signals, `io_caclr[2..0]`, and three synchronous clear signals, `io_csclr[2..0]`.

(2) Each of the three IOEs in the row I/O block can have one `io_datain` input (combinatorial or registered) and one `comb_io_datain` (combinatorial) input.

output pins (`nSTATUS` and `CONF_DONE`) and all the JTAG pins in I/O bank 3 must operate at 2.5 V because the V_{CCIO} level of SSTL-2 is 2.5 V. I/O banks 1, 2, 3, and 4 support DQS signals with DQ bus modes of × 8.

For × 8 mode, there are up to eight groups of programmable DQS and DQ pins, I/O banks 1, 2, 3, and 4 each have two groups in the 324-pin and 400-pin FineLine BGA packages. Each group consists of one DQS pin, a set of eight DQ pins, and one DM pin (see Figure 2–33). Each DQS pin drives the set of eight DQ pins within that group.

Figure 2–33. Cyclone Device DQ and DQS Groups in ×8 Mode *Note (1)*



Note to Figure 2–33:
(1) Each DQ group consists of one DQS pin, eight DQ pins, and one DM pin.

Table 2–10 shows the number of DQ pin groups per device.

Table 2–10. DQ Pin Groups (Part 1 of 2)

Device	Package	Number of × 8 DQ Pin Groups	Total DQ Pin Count
EP1C3	100-pin TQFP *(1)*	3	24
	144-pin TQFP	4	32
EP1C4	324-pin FineLine BGA	8	64
	400-pin FineLine BGA	8	64

Referenced Documents

This chapter references the following document:

- *Using PLLs in Cyclone Devices* chapter in the *Cyclone Device Handbook*

Document Revision History

Table 2–15 shows the revision history for this chapter.

Table 2–15. Document Revision History

Date and Document Version	Changes Made	Summary of Changes
May 2008 v1.6	Minor textual and style changes. Added "Referenced Documents" section.	—
January 2007 v1.5	● Added document revision history. ● Updated Figures 2–17, 2–18, 2–19, 2–20, 2–21, and 2–32.	—
August 2005 v1.4	Minor updates.	—
February 2005 v1.3	● Updated JTAG chain limits. Added test vector information. ● Corrected Figure 2-12. ● Added a note to Tables 2-17 through 2-21 regarding violating the setup or hold time.	—
October 2003 v1.2	● Updated phase shift information. ● Added 64-bit PCI support information.	—
September 2003 v1.1	Updated LVDS data rates to 640 Mbps from 311 Mbps.	—
May 2003 v1.0	Added document to Cyclone Device Handbook.	—

3. Configuration and Testing

IEEE Std. 1149.1 (JTAG) Boundary Scan Support

All Cyclone® devices provide JTAG BST circuitry that complies with the IEEE Std. 1149.1a-1990 specification. JTAG boundary-scan testing can be performed either before or after, but not during configuration. Cyclone devices can also use the JTAG port for configuration together with either the Quartus® II software or hardware using either Jam Files (**.jam**) or Jam Byte-Code Files (**.jbc**).

Cyclone devices support reconfiguring the I/O standard settings on the IOE through the JTAG BST chain. The JTAG chain can update the I/O standard for all input and output pins any time before or during user mode. Designers can use this ability for JTAG testing before configuration when some of the Cyclone pins drive or receive from other devices on the board using voltage-referenced standards. Since the Cyclone device might not be configured before JTAG testing, the I/O pins might not be configured for appropriate electrical standards for chip-to-chip communication. Programming those I/O standards via JTAG allows designers to fully test I/O connection to other devices.

The JTAG pins support 1.5-V/1.8-V or 2.5-V/3.3-V I/O standards. The TDO pin voltage is determined by the V_{CCIO} of the bank where it resides. The bank V_{CCIO} selects whether the JTAG inputs are 1.5-V, 1.8-V, 2.5-V, or 3.3-V compatible.

Cyclone devices also use the JTAG port to monitor the operation of the device with the SignalTap® II embedded logic analyzer. Cyclone devices support the JTAG instructions shown in Table 3–1.

Table 3–1. Cyclone JTAG Instructions (Part 1 of 2)

JTAG Instruction	Instruction Code	Description
`SAMPLE/PRELOAD`	00 0000 0101	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern to be output at the device pins. Also used by the SignalTap II embedded logic analyzer.
`EXTEST` *(1)*	00 0000 0000	Allows the external circuitry and board-level interconnects to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
`BYPASS`	11 1111 1111	Places the 1-bit bypass register between the `TDI` and `TDO` pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.

Operating Modes

The Cyclone architecture uses SRAM configuration elements that require configuration data to be loaded each time the circuit powers up. The process of physically loading the SRAM data into the device is called configuration. During initialization, which occurs immediately after configuration, the device resets registers, enables I/O pins, and begins to operate as a logic device. Together, the configuration and initialization processes are called command mode. Normal device operation is called user mode.

SRAM configuration elements allow Cyclone devices to be reconfigured in-circuit by loading new configuration data into the device. With real-time reconfiguration, the device is forced into command mode with a device pin. The configuration process loads different configuration data, reinitializes the device, and resumes user-mode operation. Designers can perform in-field upgrades by distributing new configuration files either within the system or remotely.

A built-in weak pull-up resistor pulls all user I/O pins to V_{CCIO} before and during device configuration.

The configuration pins support 1.5-V/1.8-V or 2.5-V/3.3-V I/O standards. The voltage level of the configuration output pins is determined by the V_{CCIO} of the bank where the pins reside. The bank V_{CCIO} selects whether the configuration inputs are 1.5-V, 1.8-V, 2.5-V, or 3.3-V compatible.

Configuration Schemes

Designers can load the configuration data for a Cyclone device with one of three configuration schemes (see Table 3–5), chosen on the basis of the target application. Designers can use a configuration device, intelligent controller, or the JTAG port to configure a Cyclone device. A low-cost configuration device can automatically configure a Cyclone device at system power-up.

4. DC and Switching Characteristics

C51004-1.7

Operating Conditions

Cyclone® devices are offered in both commercial, industrial, and extended temperature grades. However, industrial-grade and extended-temperature-grade devices may have limited speed-grade availability.

Tables 4–1 through 4–16 provide information on absolute maximum ratings, recommended operating conditions, DC operating conditions, and capacitance for Cyclone devices.

Table 4–1. Cyclone Device Absolute Maximum Ratings *Notes (1), (2)*

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCINT}	Supply voltage	With respect to ground *(3)*	–0.5	2.4	V
V_{CCIO}			–0.5	4.6	V
V_{CCA}	Supply voltage	With respect to ground *(3)*	–0.5	2.4	V
V_I	DC input voltage		–0.5	4.6	V
I_{OUT}	DC output current, per pin		–25	25	mA
T_{STG}	Storage temperature	No bias	–65	150	°C
T_{AMB}	Ambient temperature	Under bias	–65	135	°C
T_J	Junction temperature	BGA packages under bias	—	135	°C

Table 4–2. Cyclone Device Recommended Operating Conditions (Part 1 of 2)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCINT}	Supply voltage for internal logic and input buffers	*(4)*	1.425	1.575	V
V_{CCIO}	Supply voltage for output buffers, 3.3-V operation	*(4)*	3.00	3.60	V
	Supply voltage for output buffers, 2.5-V operation	*(4)*	2.375	2.625	V
	Supply voltage for output buffers, 1.8-V operation	*(4)*	1.71	1.89	V
	Supply voltage for output buffers, 1.5-V operation	*(4)*	1.4	1.6	V
V_I	Input voltage	*(3)*, *(5)*	–0.5	4.1	V

Table 4–2. Cyclone Device Recommended Operating Conditions (Part 2 of 2)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_O	Output voltage		0	V_{CCIO}	V
T_J	Operating junction temperature	For commercial use	0	85	° C
		For industrial use	–40	100	° C
		For extended-temperature use	–40	125	° C

Table 4–3. Cyclone Device DC Operating Conditions *Note (6)*

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
I_I	Input pin leakage current	$V_I = V_{CCIOmax}$ to 0 V *(8)*	–10	—	10	µA
I_{OZ}	Tri-stated I/O pin leakage current	$V_O = V_{CCIOmax}$ to 0 V *(8)*	–10	—	10	µA
I_{CC0}	V_{CC} supply current (standby) (All M4K blocks in power-down mode) *(7)*	EP1C3	—	4	—	mA
		EP1C4	—	6	—	mA
		EP1C6	—	6	—	mA
		EP1C12	—	8	—	mA
		EP1C20	—	12	—	mA
R_{CONF} *(9)*	Value of I/O pin pull-up resistor before and during configuration	$V_I = 0$ V; $V_{CCIO} = 3.3$ V	15	25	50	kΩ
		$V_I = 0$ V; $V_{CCIO} = 2.5$ V	20	45	70	kΩ
		$V_I = 0$ V; $V_{CCIO} = 1.8$ V	30	65	100	kΩ
		$V_I = 0$ V; $V_{CCIO} = 1.5$ V	50	100	150	kΩ
	Recommended value of I/O pin external pull-down resistor before and during configuration	—	—	1	2	kΩ

Table 4–4. LVTTL Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO}	Output supply voltage	—	3.0	3.6	V
V_{IH}	High-level input voltage	—	1.7	4.1	V
V_{IL}	Low-level input voltage	—	–0.5	0.7	V
V_{OH}	High-level output voltage	$I_{OH} = -4$ to -24 mA *(11)*	2.4	—	V
V_{OL}	Low-level output voltage	$I_{OL} = 4$ to 24 mA *(11)*	—	0.45	V

Table 4–10. 3.3-V PCI Specifications (Part 2 of 2)

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{OH}	High-level output voltage	I_{OUT} = –500 µA	0.9 × V_{CCIO}	—	—	V
V_{OL}	Low-level output voltage	I_{OUT} = 1,500 µA	—	—	0.1 × V_{CCIO}	V

Table 4–11. SSTL-2 Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage	—	2.375	2.5	2.625	V
V_{TT}	Termination voltage	—	V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04	V
V_{REF}	Reference voltage	—	1.15	1.25	1.35	V
V_{IH}	High-level input voltage	—	V_{REF} + 0.18	—	3.0	V
V_{IL}	Low-level input voltage	—	–0.3	—	V_{REF} – 0.18	V
V_{OH}	High-level output voltage	I_{OH} = –8.1 mA *(11)*	V_{TT} + 0.57	—	—	V
V_{OL}	Low-level output voltage	I_{OL} = 8.1 mA *(11)*	—	—	V_{TT} – 0.57	V

Table 4–12. SSTL-2 Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage	—	2.3	2.5	2.7	V
V_{TT}	Termination voltage	—	V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04	V
V_{REF}	Reference voltage	—	1.15	1.25	1.35	V
V_{IH}	High-level input voltage	—	V_{REF} + 0.18	—	V_{CCIO} + 0.3	V
V_{IL}	Low-level input voltage	—	–0.3	—	V_{REF} – 0.18	V
V_{OH}	High-level output voltage	I_{OH} = –16.4 mA *(11)*	V_{TT} + 0.76	—	—	V
V_{OL}	Low-level output voltage	I_{OL} = 16.4 mA *(11)*	—	—	V_{TT} – 0.76	V

Table 4–13. SSTL-3 Class I Specifications (Part 1 of 2)

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage	—	3.0	3.3	3.6	V
V_{TT}	Termination voltage	—	V_{REF} – 0.05	V_{REF}	V_{REF} + 0.05	V

Table 4–16. Cyclone Device Capacitance *Note (14)*

Symbol	Parameter	Typical	Unit
C_{IO}	Input capacitance for user I/O pin	4.0	pF
C_{LVDS}	Input capacitance for dual-purpose LVDS/user I/O pin	4.7	pF
C_{VREF}	Input capacitance for dual-purpose V_{REF}/user I/O pin.	12.0	pF
C_{DPCLK}	Input capacitance for dual-purpose `DPCLK`/user I/O pin.	4.4	pF
C_{CLK}	Input capacitance for CLK pin.	4.7	pF

Notes to Tables 4–1 through 4–16:

(1) Refer to the *Operating Requirements for Altera Devices Data Sheet*.

(2) Conditions beyond those listed in Table 4–1 may cause permanent damage to a device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse affects on the device.

(3) Minimum DC input is –0.5 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 4.6 V for input currents less than 100 mA and periods shorter than 20 ns.

(4) Maximum V_{CC} rise time is 100 ms, and V_{CC} must rise monotonically.

(5) All pins, including dedicated inputs, clock, I/O, and JTAG pins, may be driven before V_{CCINT} and V_{CCIO} are powered.

(6) Typical values are for T_A = 25° C, V_{CCINT} = 1.5 V, and V_{CCIO} = 1.5 V, 1.8 V, 2.5 V, and 3.3 V.

(7) V_I = ground, no load, no toggling inputs.

(8) This value is specified for normal device operation. The value may vary during power-up. This applies for all V_{CCIO} settings (3.3, 2.5, 1.8, and 1.5 V).

(9) R_{CONF} is the measured value of internal pull-up resistance when the I/O pin is tied directly to GND. R_{CONF} value will be lower if an external source drives the pin higher than V_{CCIO}.

(10) Pin pull-up resistance values will lower if an external source drives the pin higher than V_{CCIO}.

(11) Drive strength is programmable according to values in *Cyclone Architecture* chapter in the *Cyclone Device Handbook*.

(12) Overdrive is possible when a 1.5 V or 1.8 V and a 2.5 V or 3.3 V input signal feeds an input pin. Turn on "Allow voltage overdrive" for LVTTL/LVCMOS input pins in the Assignments > Device > Device and Pin Options > Pin Placement tab when a device has this I/O combination. However, higher leakage current is expected.

(13) The Cyclone LVDS interface requires a resistor network outside of the transmitter channels.

(14) Capacitance is sample-tested only. Capacitance is measured using time-domain reflections (TDR). Measurement accuracy is within ±0.5 pF.

Table 4–22. IOE Internal Timing Microparameter Descriptions

Symbol	Parameter
t_{SU}	IOE input and output register setup time before clock
t_{H}	IOE input and output register hold time after clock
t_{CO}	IOE input and output register clock-to-output delay
$t_{PIN2COMBOUT\_R}$	Row input pin to IOE combinatorial output
$t_{PIN2COMBOUT\_C}$	Column input pin to IOE combinatorial output
$t_{COMBIN2PIN\_R}$	Row IOE data input to combinatorial output pin
$t_{COMBIN2PIN\_C}$	Column IOE data input to combinatorial output pin
t_{CLR}	Minimum clear pulse width
t_{PRE}	Minimum preset pulse width
t_{CLKHL}	Minimum clock high or low time

Table 4–23. M4K Block Internal Timing Microparameter Descriptions

Symbol	Parameter
t_{M4KRC}	Synchronous read cycle time
t_{M4KWC}	Synchronous write cycle time
$t_{M4KWERESU}$	Write or read enable setup time before clock
$t_{M4KWEREH}$	Write or read enable hold time after clock
$t_{M4KBESU}$	Byte enable setup time before clock
t_{M4KBEH}	Byte enable hold time after clock
$t_{M4KDATAASU}$	A port data setup time before clock
$t_{M4KDATAAH}$	A port data hold time after clock
$t_{M4KADDRASU}$	A port address setup time before clock
$t_{M4KADDRAH}$	A port address hold time after clock
$t_{M4KDATABSU}$	B port data setup time before clock
$t_{M4KDATABH}$	B port data hold time after clock
$t_{M4KADDRBSU}$	B port address setup time before clock
$t_{M4KADDRBH}$	B port address hold time after clock
$t_{M4KDATACO1}$	Clock-to-output delay when using output registers
$t_{M4KDATACO2}$	Clock-to-output delay without output registers
$t_{M4KCLKHL}$	Minimum clock high or low time
t_{M4KCLR}	Minimum clear pulse width

Table 4–27. M4K Block Internal Timing Microparameters

Symbol	-6		-7		-8		Unit
	Min	Max	Min	Max	Min	Max	
t_{M4KRC}	—	4,379		5,035		5,691	ps
t_{M4KWC}	—	2,910		3,346		3,783	ps
$t_{M4KWERESU}$	72	—	82	—	93	—	ps
$t_{M4KWEREH}$	43	—	49	—	55	—	ps
$t_{M4KBESU}$	72	—	82	—	93	—	ps
t_{M4KBEH}	43	—	49	—	55	—	ps
$t_{M4KDATAASU}$	72	—	82	—	93	—	ps
$t_{M4KDATAAH}$	43	—	49	—	55	—	ps
$t_{M4KADDRASU}$	72	—	82	—	93	—	ps
$t_{M4KADDRAH}$	43	—	49	—	55	—	ps
$t_{M4KDATABSU}$	72	—	82	—	93	—	ps
$t_{M4KDATABH}$	43	—	49	—	55	—	ps
$t_{M4KADDRBSU}$	72	—	82	—	93	—	ps
$t_{M4KADDRBH}$	43	—	49	—	55	—	ps
$t_{M4KDATACO1}$	—	621	—	714	—	807	ps
$t_{M4KDATACO2}$	—	4,351	—	5,003	—	5,656	ps
$t_{M4KCLKHL}$	1,234	—	1,562	—	1,818	—	ps
t_{M4KCLR}	286	—	328	—	371	—	ps

Table 4–28. Routing Delay Internal Timing Microparameters

Symbol	-6		-7		-8		Unit
	Min	Max	Min	Max	Min	Max	
t_{R4}	—	261	—	300	—	339	ps
t_{C4}	—	338	—	388	—	439	ps
t_{LOCAL}	—	244	—	281	—	318	ps

External Timing Parameters

External timing parameters are specified by device density and speed grade. Figure 4–2 shows the timing model for bidirectional IOE pin timing. All registers are within the IOE.

Table 4–39. EP1C20 Row Pin Global Clock External I/O Timing Parameters

Symbol	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.417	—	2.779	—	3.140	—	ns
t_{INH}	0.000	—	0.000	—	0.000	—	ns
t_{OUTCO}	2.000	3.724	2.000	4.282	2.000	4.843	ns
t_{XZ}	—	3.645	—	4.191	—	4.740	ns
t_{ZX}	—	3.645	—	4.191	—	4.740	ns
$t_{INSUPLL}$	1.417	—	1.629	—	1.840	—	ns
t_{INHPLL}	0.000	—	0.000	—	0.000	—	ns
$t_{OUTCOPLL}$	0.500	1.667	0.500	1.917	0.500	2.169	ns
t_{XZPLL}	—	1.588	—	1.826	—	2.066	ns
t_{ZXPLL}	—	1.588	—	1.826	—	2.066	ns

External I/O Delay Parameters

External I/O delay timing parameters for I/O standard input and output adders and programmable input and output delays are specified by speed grade independent of device density.

Tables 4–40 through 4–45 show the adder delays associated with column and row I/O pins for all packages. If an I/O standard is selected other than LVTTL 4 mA with a fast slew rate, add the selected delay to the external t_{CO} and t_{SU} I/O parameters shown in Tables 4–25 through 4–28.

Table 4–40. Cyclone I/O Standard Column Pin Input Delay Adders (Part 1 of 2)

I/O Standard	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
LVCMOS	—	0	—	0	—	0	ps
3.3-V LVTTL	—	0	—	0	—	0	ps
2.5-V LVTTL	—	27	—	31	—	35	ps
1.8-V LVTTL	—	182	—	209	—	236	ps
1.5-V LVTTL	—	278	—	319	—	361	ps
SSTL-3 class I	—	–250	—	–288	—	–325	ps
SSTL-3 class II	—	–250	—	–288	—	–325	ps
SSTL-2 class I	—	–278	—	–320	—	–362	ps